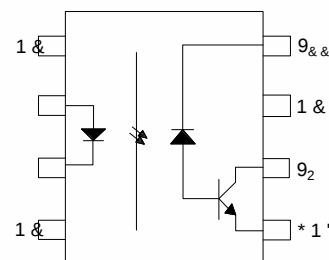




7KH SURGXFWV DUHHG %S WKR JKRXS ØHU
LV D VPDOO RXWOLHQH RYXSDIHUFV XIRX
,W FRQVLVWV RI D KLJK RXWSXW SRØE
WR D KLJK VSHHG SKRWRG IFRG Ø WWDLO
SODVWLF :623 DQG JXHUDDQW HGLWV DFQ
D FOHDUDQFH RI • PWDQGV DIQLHQW
7KHUHIRUH LW PHHGV QWXRORJLQDEOH
RI LQWHUQDWLRQDO VDIHW\ VWDQGDUG
LQ SURJUDPPDEOH XPRQWLRQDO QYUWQ
SRZHU VXSSOLHV

+LJK LVRODWLRQ 9506
&7,! 9
2SHUDWLQJ WHPSHUDWXUH WR f &
5(\$+ 5R+6 FRPSOLDQFH
+%0 + \$ 00 0 &'0 &
&4& DSSURYHG
9'(DSSURYHG
8/ DSSURYHG



/(	2XWSXW
21	/
2))	+

7HPSHUDWXUH f &

Parameter		Symbol	Value	Unit
,QSXW	)RUZDUG &XUUHQW)			
	3HDN)RUZDUG &XUUHQW		7	\$
	5HYHUVH 9ROWDJH 95			
	,QSXW 3RZHU 'LVVLSDWLRQ		3	P:
2XWSXW	6XSSO\ 9ROWDJH &&		9	
	2XWSXW 9ROWDJH 92			

	2XWSXW &XUUHQW	,2		
	2XWSXW 3RZHU 'LVVLSDWLRQ	3	P :	
7RWDO 3RZHU 'LVVLSDWLRQ	3WRW		P :	
,VRODWLRQ 9ROWDJH	9LVR	8	9UPV	
2SHUDWLQJ 7HPSHUDWXUH	7RSU	a		
-XQFWLRQ 7HPSHUDWXUH	7M			
6WRUDJH 7HPSHUDWXUH	7VWJ	a		
6ROGHULQJ 7HPSHUDWXUH	7VRO			

iii

&RPPRQ 0RGH
7UDQVLHQW
,PPXQLW\ DW /R JL F
+LJK

), P\$
9&0 9SS
5/ N gcV V • € ~D Gv5l

FIG.7: /RZ /HYHO 2XWDSJHWY9RQ\$PELHQWVFIG.8: 3URSDJDWLRQ 'HOD\ YV /RDG
7HP SHUDWXUH 5HVLVWDQFH

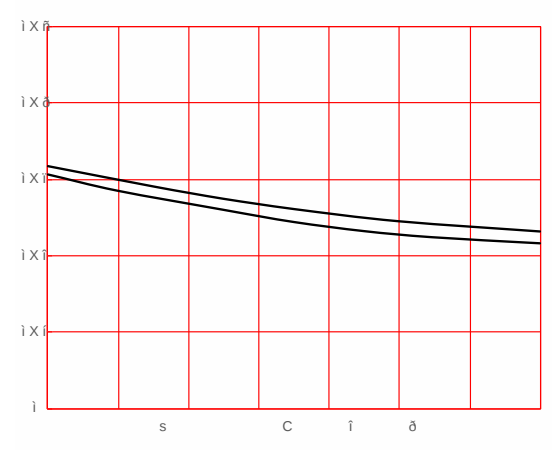


Fig.10: Test Circuit of tPHL, tPLH

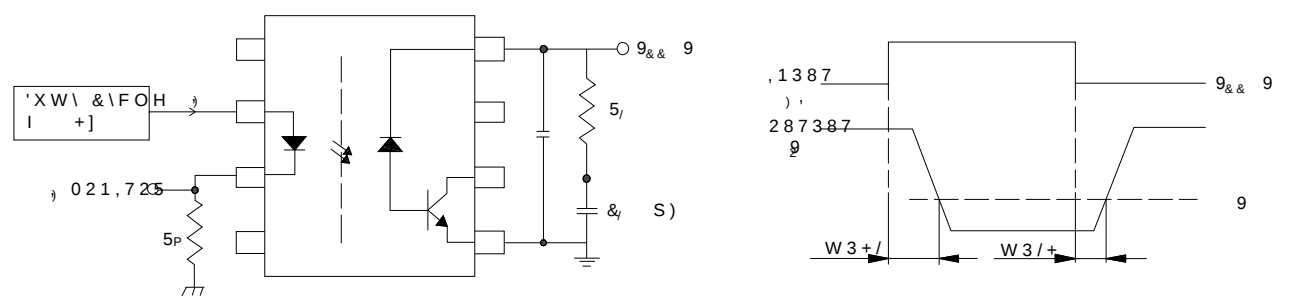
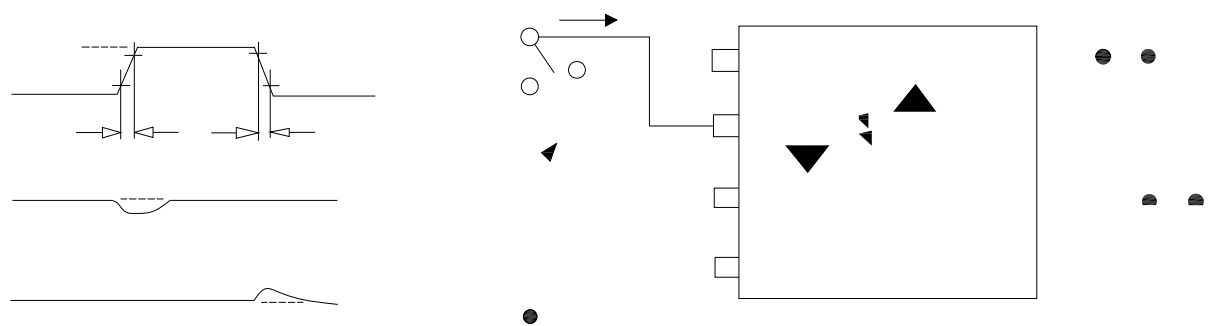
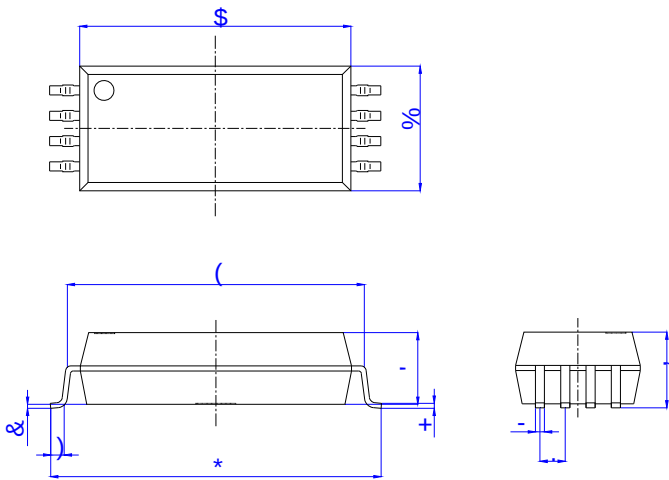
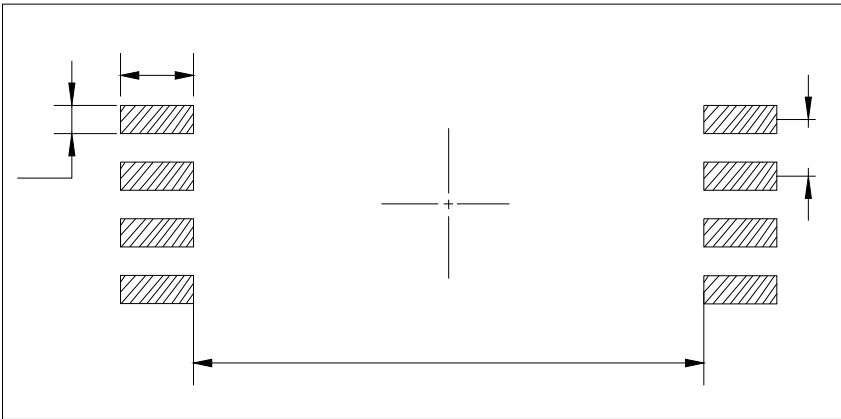


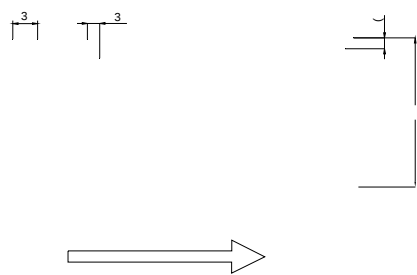
Fig.11: Test Circuit for Transient Immunity and Typical Waveforms





5HI	'LPHQVLRQV					
	0LOOLPHWHUV			,QFKHV		
	0LQ	7\ S	0D[	0LQ	7\ S	0D[
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Profile Feature	Sn-Pb Assembly Profile	Pb-Free Assembly Profile
7HP SHUDWXUH 0LQ	7VPLQ	
7HP SHUDWXUH 0D[	7VPD[	

1RWH

5HIORZ VROGHULQJ LV UHFRPPHQGHG/ DWRZQH QHPSHUDWXUDQW DQW
\$YRLG GLUHFWRUHQWDFSRPHQZDQWWRUDFRU H[FHHGLQJ LWV PD
VWRUDJH WHPSHUDWXUH
\$SSOLFDFWLRQ RKHUSRYXERHQWLSOHGDDWHG WHPSHUDWXUHV ,QV
VFHQDULRV DQHPSSOLHQWRHFFHHG 1
(QVXUH WKH FRPSRQHQRW KDV FRROHG WRDFHFWLRQZLHPSHUDWXU
PDQXIDFWXULQJ VWHSV
7KH FRPSRQHQRW KDV DQKHODUZHQRW VWRUHG XQGHU

06I OHYH G 06I S